National Semiconductor

March 1993

74ACQ273 • 54ACTQ/74ACTQ273 Quiet Series Octal D Flip-Flop

General Description

The 'AC/'ACT273 has eight edge-triggered D-type flip-flops with individual D inputs and Q outputs. The common buffered Clock (CP) and Master Reset ($\overline{MR}$) input load and reset (clear) all flip-flops simultaneously.

The register is fully edge-triggered. The state of each D input, one setup time before the LOW-to-HIGH clock transition, is transferred to the corresponding flip-flop's Q output.

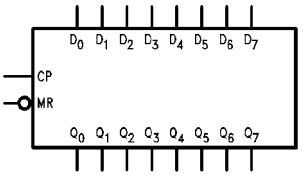
All outputs will be forced LOW independently of Clock or Data inputs by a LOW voltage level on the $\overline{MR}$ input. The device is useful for applications where the true output only is required and the Clock and Master Reset are common to all storage elements.

The 'ACQ/'ACTQ utilizes NSC Quiet Series technology to guarantee quiet output switching and improved dynamic threshold performance. FACT Quiet Series™ features GTO™ output control and undershoot corrector in addition to a split ground bus for superior performance.

Features

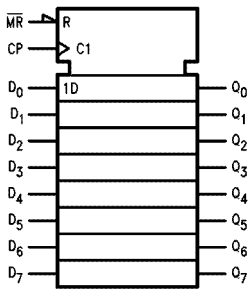
- I_{CC} reduced by 50%
- Guaranteed simultaneous switching noise level and dynamic threshold performance
- Guaranteed pin-to-pin skew AC performance
- Improved latch-up immunity
- Buffered common clock and asynchronous master reset
- Outputs source/sink 24 mA
- Faster prop delays than the standard 'AC/'ACT273
- 4 kV minimum ESD immunity
- Standard Military Drawing (SMD)
  — 'ACTQ273: 5962-89735

Logic Symbols



TL/F/10585–1

IEEE/IEC

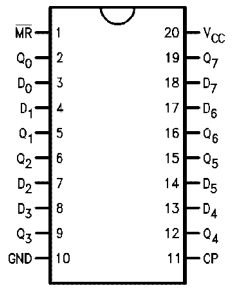


TL/F/10585–2

Pin Names	Description
D_0–D_7	Data Inputs
$\overline{MR}$	Master Reset
CP	Clock Pulse Input
Q_0–Q_7	Data Outputs

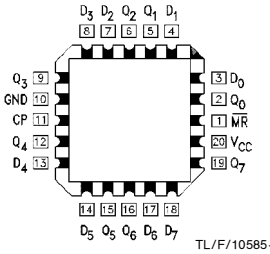
Connection Diagrams

Pin Assignment for DIP, Flatpak and SOIC



TL/F/10585–3

Pin Assignment for LCC



TL/F/10585–4

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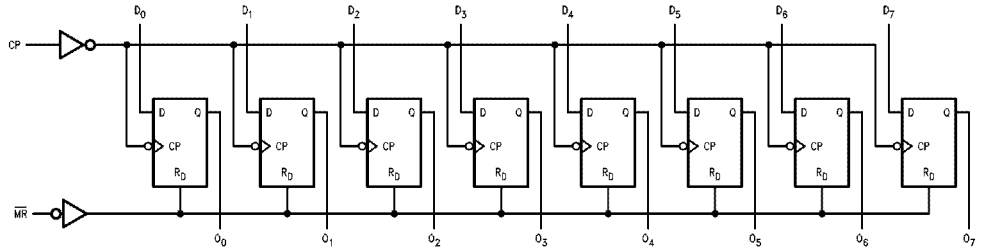
Mode Select-Function Table

Operating Mode	Inputs			Outputs
	$\overline{MR}$	CP	D_n	Q_n
Reset (Clear)	L	X	X	L
Load '1'	H	⌐/	H	H
Load '0'	H	⌐/	L	L

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
⌐/ = LOW-to-HIGH Transition

Logic Diagram



TL/F/10585–5

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Supply Voltage (V_{CC})	−0.5V to +7.0V
DC Input Diode Current (I_{IK})	
V_I = −0.5V	−20 mA
V_I = V_{CC} + 0.5V	+20 mA
DC Input Voltage (V_I)	−0.5V to V_{CC} + 0.5V
DC Output Diode Current (I_{OK})	
V_O = −0.5V	−20 mA
V_O = V_{CC} + 0.5V	+20 mA
DC Output Voltage (V_O)	−0.5V to V_{CC} + 0.5V
DC Output Source or Sink Current (I_O)	±50 mA
DC V_{CC} or Ground Current per Output Pin (I_{CC} or I_{GND})	±50 mA
Storage Temperature (T_{STG})	−65°C to +150°C
DC Latch-up Source or Sink Current	±300 mA
Junction Temperature (T_J)	
CDIP	175°C
PDIP	140°C

Note 1: Absolute maximum ratings are those values beyond which damage to the device may occur. The databook specifications should be met, without exception, to ensure that the system design is reliable over its power supply, temperature, and output/input loading variables. National does not recommend operation of FACT circuits outside databook specifications.

Recommended Operating Conditions

Supply Voltage (V_{CC})	
'ACQ	2.0V to 6.0V
'ACTQ	4.5V to 5.5V
Input Voltage (V_I)	0V to V_{CC}
Output Voltage (V_O)	0V to V_{CC}
Operating Temperature (T_A) (Note 2)	
74ACQ/ACTQ	−40°C to +85°C
54ACTQ	−55°C to +125°C
Minimum Input Edge Rate ΔV/Δt 'ACQ Devices V_{IN} from 30% to 70% of V_{CC} V_{CC} @ 3.0V, 4.5V, 5.5V	125 mV/ns
Minimum Input Edge Rate ΔV/Δt 'ACTQ Devices V_{IN} from 0.8V to 2.0V V_{CC} @ 4.5V, 5.5V	125 mV/ns

Note: All commercial packaging is not recommended for applications requiring greater than 2000 temperature cycles from −40°C to +125°C.

DC Characteristics for 'ACQ Family Devices

Symbol	Parameter	V_{CC} (V)	74ACQ T_A = +25°C	74ACQ T_A = −40°C to +85°C	Units	Conditions
			Typ	Guaranteed Limits		
V_{IH}	Minimum High Level Input Voltage	3.0	1.5	2.1	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		4.5	2.25	3.15		
		5.5	2.75	3.85		
V_{IL}	Maximum Low Level Input Voltage	3.0	1.5	0.9	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
		4.5	2.25	1.35		
		5.5	2.75	1.65		
V_{OH}	Minimum High Level Output Voltage	3.0	2.99	2.9	V	I_{OUT} = −50 μA
		4.5	4.49	4.4		
		5.5	5.49	5.4		
		3.0		2.56	V	*V_{IN} = V_{IL} or V_{IH} I_{OH} −12 mA
		4.5		3.86		
		5.5		4.86		I_{OH} −24 mA
V_{OL}	Maximum Low Level Output Voltage	3.0	0.002	0.1	V	I_{OUT} = 50 μA
		4.5	0.001	0.1		
		5.5	0.001	0.1		
		3.0		0.36	V	*V_{IN} = V_{IL} or V_{IH} I_{OL} 12 mA
		4.5		0.36		
		5.5		0.36		I_{OL} 24 mA
I_{IN}	Maximum Input Leakage Current	5.5		±0.1	μA	V_I = V_{CC}, GND (Note 1)

*All outputs loaded; thresholds on input associated with output under test.

Note 1: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

DC Characteristics for 'ACQ Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	74ACQ $T_A = +25°C$		74ACQ $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits			
I_{OLD}	†Minimum Dynamic Output Current	5.5			75	mA	V_{OLD} = 1.65V Max
I_{OHD}		5.5			−75	mA	V_{OHD} = 3.85V Min
I_{CC}	Maximum Quiescent Supply Current	5.5		4.0	40.0	μA	$V_{IN} = V_{CC}$ or GND (Note 1)
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	1.1	1.5		V	*Figures 2-12, 13* (Notes 2, 3)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	−0.6	−1.2		V	*Figures 2-12, 13* (Notes 2, 3)
V_{IHD}	Minimum High Level Dynamic Input Voltage	5.0	3.1	3.5		V	(Notes 2, 4)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	5.0	1.9	1.5		V	(Notes 2, 4)

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

Note 1: I_{IN} and I_{CC} @ 3.0V are guaranteed to be less than or equal to the respective limit @ 5.5V V_{CC}.

Note 2: Plastic DIP package.

Note 3: Max number of outputs defined as (n). Data inputs are driven 0V to 5V. One output @ GND.

Note 4: Max number of Data Inputs (n) switching. (n − 1) Inputs switching 0V to 5V ('ACQ). Input-under-test switching: 5V to threshold (V_{ILD}), 0V to threshold (V_{IHD}) f = 1 MHz.

DC Characteristics for 'ACTQ Family Devices

Symbol	Parameter	V_{CC} (V)	74ACTQ $T_A = +25°C$		54ACTQ $T_A = -55°C$ to $+125°C$	74ACTQ $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits				
V_{IH}	Minimum High Level Input Voltage	4.5 5.5	1.5 1.5	2.0 2.0	2.0 2.0	2.0 2.0	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{IL}	Maximum Low Level Input Voltage	4.5 5.5	1.5 1.5	0.8 0.8	0.8 0.8	0.8 0.8	V	V_{OUT} = 0.1V or V_{CC} − 0.1V
V_{OH}	Minimum High Level Output Voltage	4.5 5.5	4.49 5.49	4.4 5.4	4.4 5.4	4.4 5.4	V	I_{OUT} = −50 μA
		4.5 5.5		3.86 4.86	3.7 4.7	3.76 4.76	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OH} −24 mA −24 mA
V_{OL}	Maximum Low Level Output Voltage	4.5 5.5	0.001 0.001	0.1 0.1	0.1 0.1	0.1 0.1	V	I_{OUT} = 50 μA
		4.5 5.5		0.36 0.36	0.50 0.50	0.44 0.44	V	*$V_{IN} = V_{IL}$ or V_{IH} I_{OL} 24 mA 24 mA
I_{IN}	Maximum Input Leakage Current	5.5		±0.1	±1.0	±1.0	μA	$V_I = V_{CC}$, GND
I_{CCT}	Maximum I_{CC}/Input	5.5	0.6		1.6	1.5	mA	$V_I = V_{CC}$ − 2.1V

*All outputs loaded; thresholds on input associated with output under test.

†Maximum test duration 2.0 ms, one output loaded at a time.

DC Characteristics for 'ACTQ Family Devices (Continued)

Symbol	Parameter	V_{CC} (V)	74ACTQ $T_A = +25°C$		54ACTQ $T_A = -55°C$ to $+125°C$	74ACTQ $T_A = -40°C$ to $+85°C$	Units	Conditions
			Typ	Guaranteed Limits				
I_{OLD}	†Minimum Dynamic Output Current	5.5			50	75	mA	V_{OLD} = 1.65V Max
I_{OHD}		5.5			−50	−75	mA	V_{OHD} = 3.85V Min
I_{CC}	Maximum Quiescent Supply Current	5.5		4.0	80.0	40.0	μA	$V_{IN} = V_{CC}$ or GND (Note 1)
V_{OLP}	Quiet Output Maximum Dynamic V_{OL}	5.0	1.1	1.5			V	*Figures 2-12, 13* (Notes 2, 3)
V_{OLV}	Quiet Output Minimum Dynamic V_{OL}	5.0	−0.6	−1.2			V	*Figures 2-12, 13* (Notes 2, 3)
V_{IHD}	Minimum High Level Dynamic Input Voltage	5.0	1.9	2.2			V	(Notes 2, 4)
V_{ILD}	Maximum Low Level Dynamic Input Voltage	5.0	1.2	0.8			V	(Notes 2, 4)

†Maximum test duration 2.0 ms, one output loaded at a time.

Note 1: I_{CC} for 54ACTQ @ 25°C is identical to 74ACTQ @ 25°C.

Note 2: Plastic DIP package.

Note 3: Max number of outputs defined as (n). n − 1 Data inputs are driven 0V to 3V; one output @ GND.

Note 4: Max number of Data Inputs (n) switching. (n − 1) Inputs switching 0V to 3V ('ACTQ). Input-under-test switching: 3V to threshold (V_{ILD}), 0V to threshold (V_{IHD}) f = 1 MHz.

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACQ $T_A = +25°C$, $C_L = 50$ pF			74ACQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	
f_{max}	Maximum Clock Frequency	3.3 5.0	90 140			75 125		MHz
t_{PLH}	Propagation Delay CP to Q_n	3.3 5.0	4.0 3.0	8.0 5.5	12.5 9.0	3.0 2.5	14.0 10.0	ns
t_{PHL}	Propagation Delay CP to Q_n	3.3 5.0	4.0 3.0	8.5 6.0	13.0 10.0	3.5 2.5	14.5 11.0	ns
t_{PHL}	Propagation Delay $\overline{MR}$ to Q_n	3.3 5.0	4.0 3.0	8.5 6.5	13.0 10.0	3.5 2.5	14.0 10.5	ns
t_{OSHL}, t_{OSLH}	Output to Output Skew**	3.3 5.0		1.0 0.5	1.5 1.0		1.5 1.0	ns

*Voltage Range 5.0 is 5.0V ±0.5V
Voltage Range 3.3 is 3.3V ±0.3V

**Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design. Not tested.

AC Operating Requirements

Symbol	Parameter	V_{CC}* (V)	74ACQ $T_A = +25°C$, $C_L = 50$ pF		74ACQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Typ	Guaranteed Minimum		
t_s	Setup Time, HIGH or LOW D_n to CP	3.3 5.0		5.0 4.0	6.0 4.5	ns
t_h	Hold Time, HIGH or LOW D_n to CP	3.3 5.0		0.0 1.0	0.0 1.0	ns
t_w	Clock Pulse Width HIGH or LOW	3.3 5.0		5.5 4.0	6.0 4.5	ns
t_w	$\overline{MR}$ Pulse Width HIGH or LOW	3.3 5.0		5.5 4.0	6.0 4.5	ns
t_w	Recovery Time $\overline{MR}$ to CP	3.3 5.0		4.0 3.0	4.5 3.0	ns

*Voltage Range 5.0 is 5.0V ±0.5V
Voltage Range 3.3 is 3.3V ±0.3V

AC Electrical Characteristics

Symbol	Parameter	V_{CC}* (V)	74ACTQ $T_A = +25°C$, $C_L = 50$ pF			54ACTQ $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF		74ACTQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF		Units
			Min	Typ	Max	Min	Max	Min	Max	
f_{max}	Maximum Clock Frequency	5.0		189	125		85		110	MHz
t_{PHL}, t_{PLH}	Propagation Delay Clock to Output	5.0	1.5	6.5	8.5	1.5	10.0	1.5	9.0	ns
t_{PHL}	Propagation Delay $\overline{MR}$ to Output	5.0	1.5	7.0	9.0	1.5	11.0	1.5	9.5	ns
t_{OSHL}, t_{OSLH}	Output to Output Skew** Data to Ouput	5.0		0.5	1.0				1.0	ns

*Voltage Range 5.0 is 5.0V ±0.5V.
**Skew is defined as the absolute value of the difference between the actual propagation delay for any two outputs within the same packaged device. The specification applies to any outputs switching in the same direction, either HIGH to LOW (t_{OSHL}) or LOW to HIGH (t_{OSLH}). Parameter guaranteed by design. Not tested.

AC Operating Requirements

Symbol	Parameter	V_{CC}* (V)	74ACTQ $T_A = +25°C$, $C_L = 50$ pF		54ACTQ $T_A = -55°C$ to $+125°C$, $C_L = 50$ pF	74ACTQ $T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Typ	Guaranteed Minimum			
t_s	Setup Time, HIGH or LOW Data to CP	5.0	1.0	3.5	5.0	3.5	ns
t_h	Hold Time, HIGH or LOW Data to CP	5.0	−0.5	1.5	2.0	1.5	ns
t_w	Clock Pulse Width HIGH or LOW	5.0	2.0	4.0	5.0	4.0	ns
t_w	$\overline{MR}$ Pulse Width HIGH or LOW	5.0	1.5	4.0	5.0	4.0	ns
t_{rec}	Recovery Time $\overline{MR}$ to CP	5.0	0.5	3.0	4.0	3.0	ns

*Voltage Range 5.0 is 5.0V ±0.5V

Capacitance

Symbol	Parameter	Typ	Units	Conditions
C_{IN}	Input Capacitance	4.5	pF	V_{CC} = OPEN
C_{PD}	Power Dissipation Capacitance	40.0	pF	V_{CC} = 5.0V

FACT Noise Characteristics

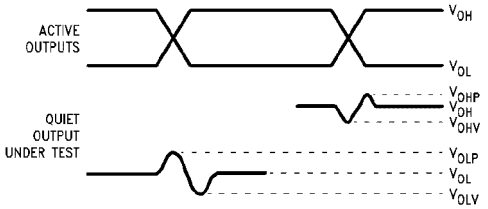
The setup of a noise characteristics measurement is critical to the accuracy and repeatability of the tests. The following is a brief description of the setup used to measure the noise characteristics of FACT.

Equipment:

Hewlett Packard Model 8180A Word Generator
PC-163A Test Fixture
Tektronics Model 7854 Oscilloscope

Procedure:

1. Verify Test Fixture Loading: Standard Load 50 pF, 500Ω.
2. Deskew the word generator so that no two channels have greater than 150 ps skew between them. This requires that the oscilloscope be deskewed first. Swap out the channels that have more than 150 ps of skew until all channels being used are within 150 ps. It is important to deskew the word generator channels before testing. This will ensure that the outputs switch simultaneously.
3. Terminate all inputs and outputs to ensure proper loading of the outputs and that the input levels are at the correct voltage.
4. Set V_{CC} to 5.0V.
5. Set the word generator to toggle all but one output at a frequency of 1 MHz. Greater frequencies will increase DUT heating and affect the results of the measurement.



TL/F/10585–6

FIGURE 1. Quiet Output Noise Voltage Waveforms

Note A. V_{OHV} and V_{OLP} are measured with respect to ground reference.

Note B. Input pulses have the following characteristics: f = 1 MHz, t_r = 3 ns, t_f = 3 ns, skew < 150 ps.

6. Set the word generator input levels at 0V LOW and 3V HIGH for ACT devices and 0V LOW and 5V HIGH for AC devices. Verify levels with a digital volt meter.

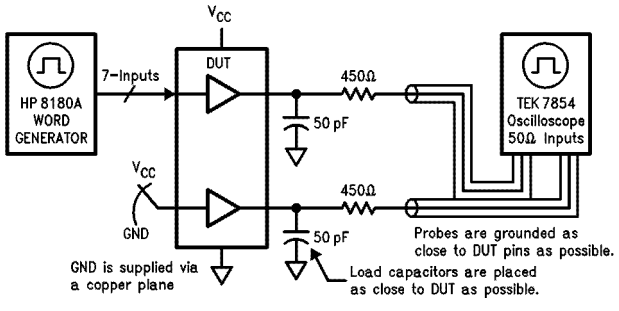
FACT Noise Characteristics (Continued)

V_{OLP}/V_{OLV} and V_{OHP}/V_{OHV}:

- Determine the quiet output pin that demonstrates the greatest noise levels. The worst case pin will usually be the furthest from the ground pin. Monitor the output voltages using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- Measure V_{OLP} and V_{OLV} on the quiet output during the HL transition. Measure V_{OHP} and V_{OHV} on the quiet output during the LH transition.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.

V_{ILD} and V_{IHD}:

- Monitor one of the switching outputs using a 50Ω coaxial cable plugged into a standard SMB type connector on the test fixture. Do not use an active FET probe.
- First increase the input LOW voltage level, V_{IL}, until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input LOW voltage level at which oscillation occurs is defined as V_{ILD}.
- Next increase the input HIGH voltage level on the word generator, V_{IH} until the output begins to oscillate. Oscillation is defined as noise on the output LOW level that exceeds V_{IL} limits, or on output HIGH levels that exceed V_{IH} limits. The input HIGH voltage level at which oscillation occurs is defined as V_{IHD}.
- Verify that the GND reference recorded on the oscilloscope has not drifted to ensure the accuracy and repeatability of the measurements.



TL/F/10585–7

FIGURE 2. Simultaneous Switching Test Circuit

Ordering Information

The device number is used to form part of a simplified purchasing code where a package type and temperature range are defined as follows:

74ACTQ 273 P C QR

Temperature Range Family
- 74ACQ = Commercial
- 74ACTQ = Commercial TTL-Compatible
- 54ACTQ = Military TTL-Compatible

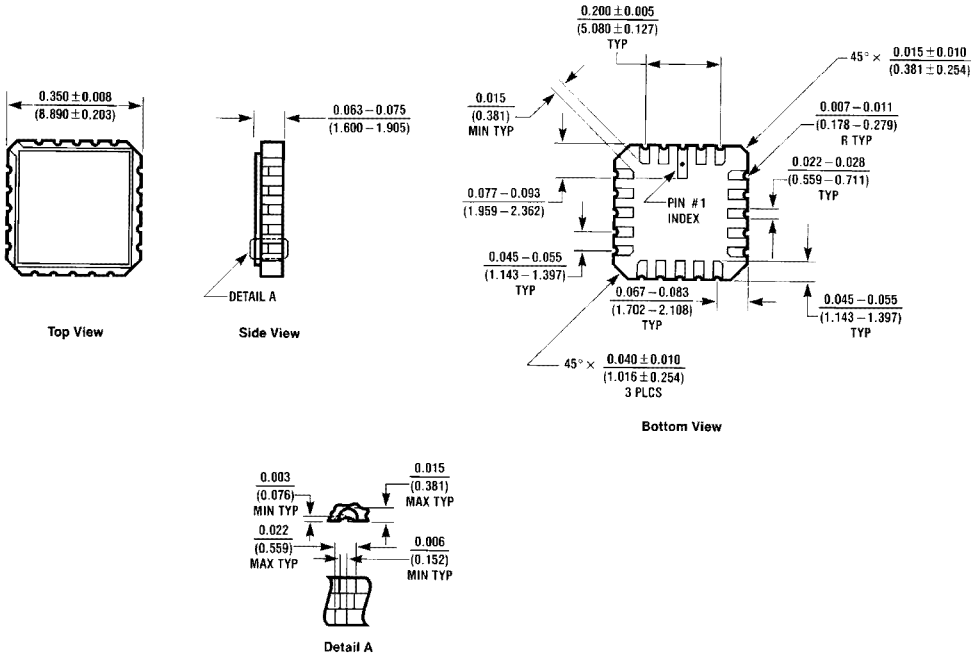
Device Type

Package Code
- P = Plastic DIP
- D = Ceramic DIP
- F = Flatpak
- L = Leadless Ceramic Chip Carrier (LCC)
- S = Small Outline Package (SOIC)

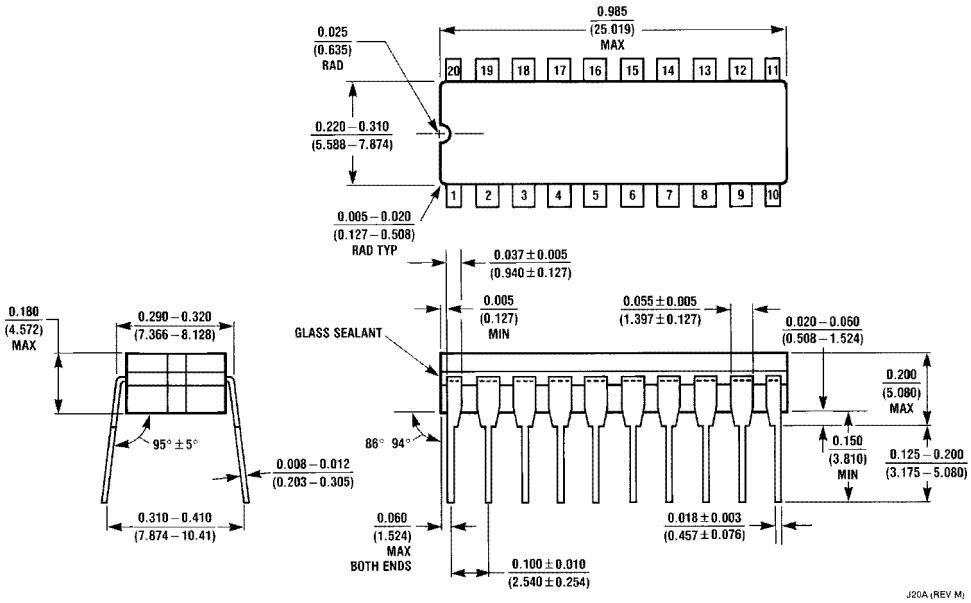
Temperature Range
- C = Commercial (−40°C to +85°C)
- M = Military (−55°C to +125°C)

Special Variations
- X = Device shipped in 13″ reels
- QR = Commercial grade device with burn-in
- QB = Military grade device with environmental and burn-in processing shipped in tubes

Physical Dimensions inches (millimeters)

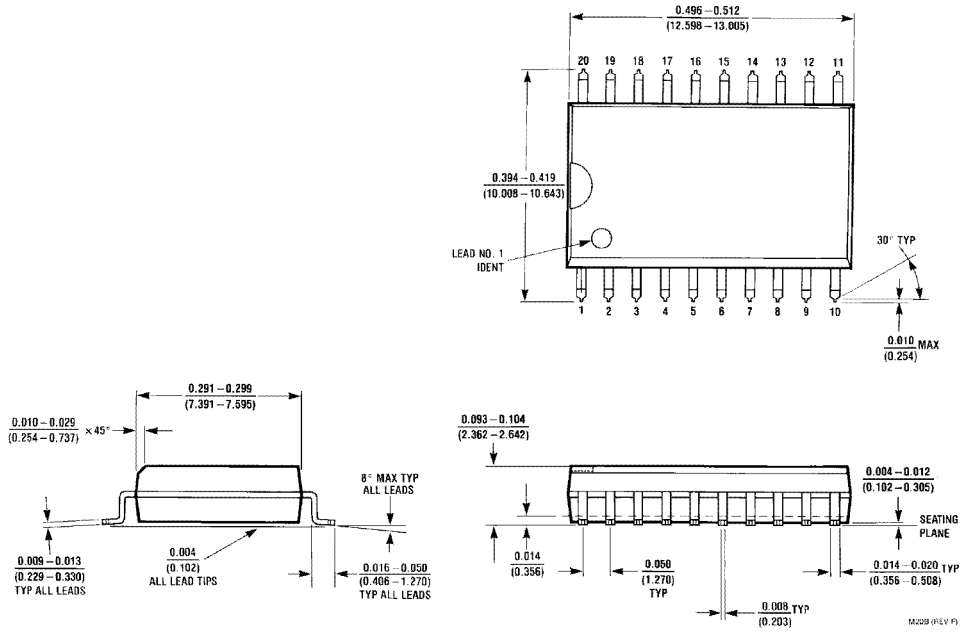


20-Terminal Ceramic Leadless Chip Carrier (L)
NS Package Number E20A

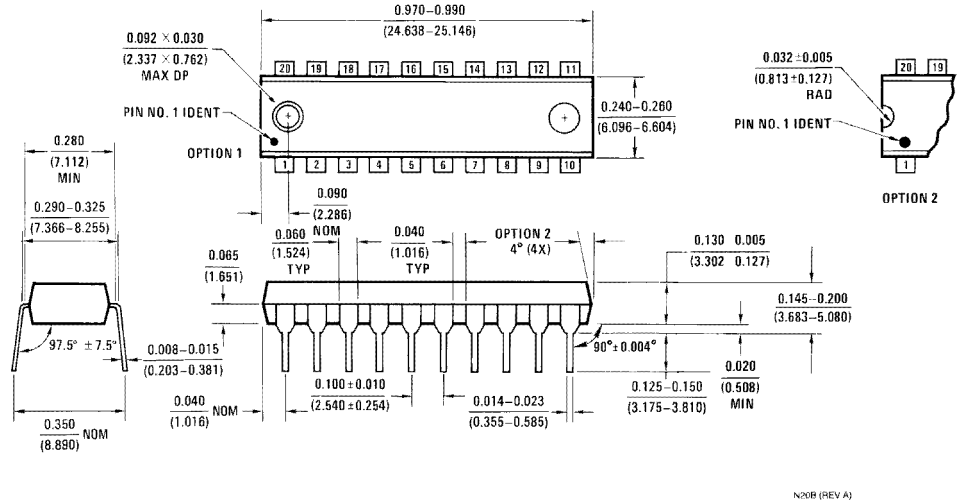


20-Lead Ceramic Dual-In-Line Package (D)
NS Package Number J20A

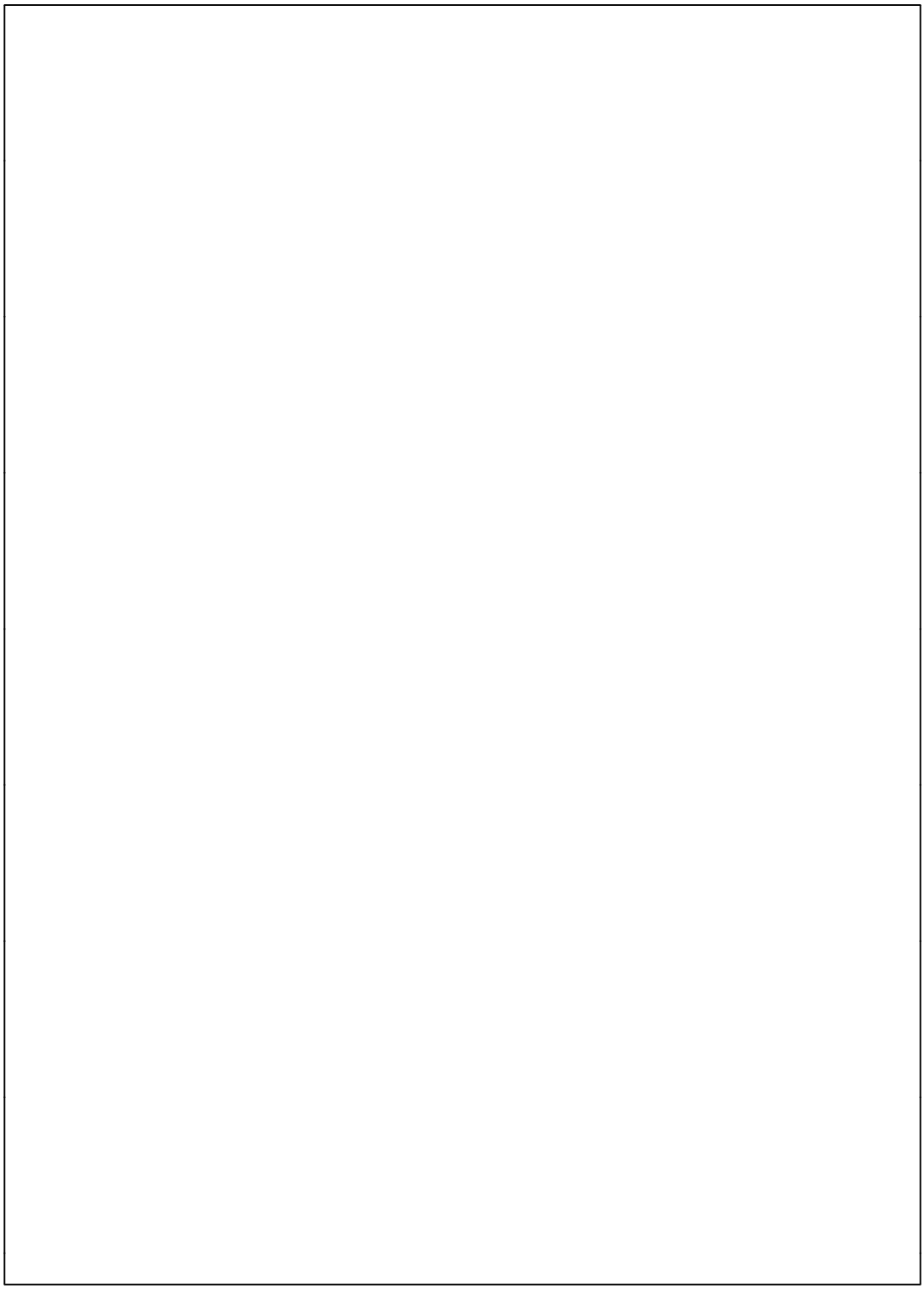
Physical Dimensions inches (millimeters) (Continued)



20-Lead Small Outline Integrated Circuit (S)
NS Package Number M20B

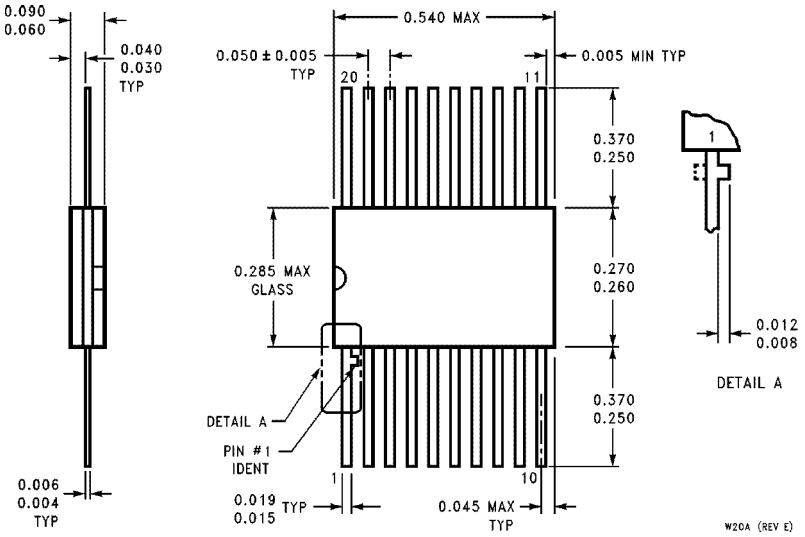


20-Lead Plastic Dual-In-Line Package (P)
NS Package Number N20B



Physical Dimensions inches (millimeters) (Continued)

Lit. # 114671



20 Lead Ceramic Flatpak (F)
NS Package Number W20A

LIFE SUPPORT POLICY

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

National Semiconductor Corporation
2900 Semiconductor Drive
P.O. Box 58090
Santa Clara, CA 95052-8090
Tel: 1(800) 272-9959
TWX: (910) 339-9240

National Semiconductor GmbH
Livry-Gargan-Str. 10
D-82256 Fürstenfeldbruck
Germany
Tel: (81-41) 35-0
Telex: 527649
Fax: (81-41) 35-1

National Semiconductor Japan Ltd.
Sumitomo Chemical
Engineering Center
Bldg. 7F
1-7-1, Nakase, Mihama-Ku
Chiba-City,
Ciba Prefecture 261
Tel: (043) 299-2300
Fax: (043) 299-2500

National Semiconductor Hong Kong Ltd.
13th Floor, Straight Block,
Ocean Centre, 5 Canton Rd.
Tsimshatsui, Kowloon
Hong Kong
Tel: (852) 2737-1600
Fax: (852) 2736-9960

National Semiconductores Do Brazil Ltda.
Rue Deputado Lacorda Franco
120-3A
Sao Paulo-SP
Brazil 05418-000
Tel: (55-11) 212-5066
Telex: 391-1131931 NSBR BR
Fax: (55-11) 212-1181

National Semiconductor (Australia) Pty, Ltd.
Building 16
Business Park Drive
Monash Business Park
Nottinghill, Melbourne
Victoria 3168 Australia
Tel: (3) 558-9999
Fax: (3) 558-9998